

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re U.S. Application of:	)	
Ki-Ryong YOO, et al.	)	
Application No.: 10/549,928	)	International Application No.: PCT/KR04/00592
Filed: September 20, 2005	)	International Appl. Filing Date: 18-Mar-2004
For: APPARATUS FOR CUTTING GLASS PLATE	)	
	)	

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

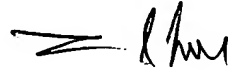
In accordance with the provisions of 37 C.F.R. 1.56, 1.97 and 1.98, the attention of the Patent and Trademark Office is hereby directed to the attached information. It is respectfully requested that the information be expressly considered by the Examiner.

These references were cited in an International Search Report dated 17 May 2004. A copy of JP 63 016893, as listed in the Search Report, is not currently available. However, an English language Abstract of the same is attached hereto. No further elaboration is believed necessary. Copies of the search report and cited art are submitted herewith in accordance with 37 C.F.R. 1.98(a).

AUTHORIZATION

No fee is required. The Commissioner is hereby authorized to charge any additional fees which may be required for this submission, or credit any overpayment to deposit account no. 50-2036.

Respectfully submitted,



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<b>LIST OF ART CITED BY APPLICANT</b>  <b>(PTO-1449)</b>					ATTY. DOCKET NO. 87408.2200		SERIAL NO. 10/549,928	
					APPLICANT Ki-Ryong YOO, et al.			
					FILING DATE September 20, 2005		GROUP not yet assigned	

U.S. PATENT DOCUMENTS							
	EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE
A		3,777,280	12/04/73	Pohl	331	94.5	06/21/72
B							
C							
D							
E							
F							
G							
H							
I							
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FOREIGN PATENT DOCUMENTS							
	EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation
U		0062484	10/13/82	Europe			
V		63016893	01/23/88	Japan			Abs
W							
X							
Y							
Z							
AA							
BB							
CC							
DD							
EE							

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)	
FF	
GG	
HH	
II	
JJ	
KK	
LL	

EXAMINER	DATE CONSIDERED
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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.